SN54ALS29823, SN74ALS29823 9-BIT BUS-INTERFACE FLIP-FLOPS WITH 3-STATE OUTPUTS

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- Functionally Equivalent to AMD's AM29823
- Provide Extra Data Width Necessary for Wider Address/Data Paths or Buses With Parity
- Outputs Have Undershoot-Protection Circuitry
- Power-Up High-Impedance State
- Buffered Control Inputs Reduce dc Loading Effects
- Package Options Include Plastic Small-Outline (DW) Packages and Standard Plastic (NT) and Ceramic (JT) 300-mil DIPs

24 V_{CC} OE Π_1 1D []2 23 1Q 2D 🛮 3 22 1 2Q 3D **[**]4 21 3Q 4D 🛮 5 20 1 4Q 5D []6 19 7 5Q 18 1 6Q 6D **∏**7 17 7Q 7D **∏**8 8D **1**9 16 8Q 15 9Q 9D [10 CLR II1 14 TCLKEN GND 12 13 CLK

SN54ALS29823...JT PACKAGE

SN74ALS29823...DW OR NT PACKAGE

(TOP VIEW)

description

These 9-bit flip-flops feature 3-state outputs designed specifically for driving highly capacitive

or relatively low-impedance loads. They are particularly suitable for implementing wider buffer registers, I/O ports, bidirectional bus drivers, parity bus interfacing, and working registers.

With the clock-enable $(\overline{\text{CLKEN}})$ input low, the <u>nine D-type</u> edge-triggered flip-flops enter data on the low-to-high transitions of the clock (CLK) input. Taking $\overline{\text{CLKEN}}$ high disables the clock buffer, latching the outputs. The 'ALS29823 have noninverting data (D) inputs. Taking the clear $(\overline{\text{CLR}})$ input low causes the nine Q outputs to go low independently of the clock.

A buffered output-enable (\overline{OE}) input places the nine outputs in either a normal logic state (high or low logic levels) or a high-impedance state. The outputs also are in the high-impedance state during power-up and power-down conditions. The outputs remain in the high-impedance state while the device is powered down. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

OE does not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54ALS29823 is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74ALS29823 is characterized for operation from 0° C to 70° C.

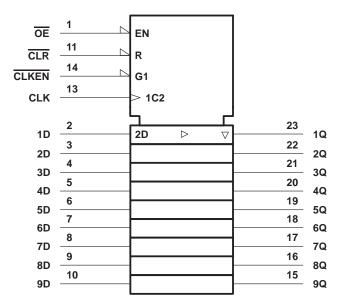
FUNCTION TABLE (each flip-flop)

		INPUTS					
ŌĒ	CLR	CLKEN	CLK	D	OUTPUT Q		
L	L	Х	Χ	Χ	L		
L	Н	L	\uparrow	Н	Н		
L	Н	L	\uparrow	L	L		
L	Н	Н	Χ	Χ	Q ₀		
Н	Χ	Χ	Χ	Χ	Z		

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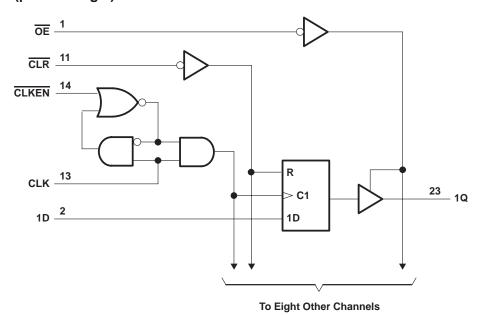
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logic symbol†



 $^{^\}dagger$ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	7 V
Input voltage, V _I	5.5 V
Voltage applied to a disabled high-impedance output	
Operating free-air temperature range, T _A : SN54ALS29823	-55°C to 125°C
Storage temperature range	-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			SN5	SN54ALS29823		UNIT	
			MIN	NOM	MAX	UNII	
Vcc	Supply voltage		4.5	5	5.5	V	
VIH	High-level input voltage		2			V	
V_{IL}	Low-level input voltage				0.8	V	
ІОН	High-level output current				-18	mA	
loL	Low-level output current				32	mA	
	Pulse duration	CLR low	7			J "	
t _W	ruise duration	CLK high or low	8			ns	
		CLR inactive	7				
t _{su}	Setup time before CLK↑	Data	4			ns	
		CLKEN high or low	8				
4.	H.H.C	CLKEN	2			no	
th	Hold time after CLK↑	Data				ns	
TA	Operating free-air temperature	·	-55	25	125	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TED TOTAL CONDITIONS		SN5	SN54ALS298		LINUT
PARAMETER	TEST C	TEST CONDITIONS		TYP‡	MAX	UNIT
VIK	$V_{CC} = 4.5 V$,	$I_{I} = -18 \text{ mA}$			-1.2	V
Vou	V 45V	I _{OH} = -12 mA	2.4	3.3		V
VOH	V _{CC} = 4.5 V	$I_{OH} = -18 \text{ mA}$	2			V
V _{OL}	$V_{CC} = 4.5 V$,	I _{OL} = 32 mA		0.25	0.5	V
IOZH	$V_{CC} = 5.5 V$,	V _O = 2.4 V			50	μΑ
lozL	$V_{CC} = 5.5 V$,	V _O = 0.4 V			-50	μΑ
Ιμ	$V_{CC} = 5.5 V$,	V _I = 5.5 V			0.1	mA
lін	$V_{CC} = 5.5 V$,	V _I = 2.7 V			20	μΑ
I _{IL}	$V_{CC} = 5.5 V$,	V _I = 0.4 V			-0.5	mA
I _{OS} §	V _{CC} = 5.5 V,	VO = 0	-75		-250	mA
		Outputs high			90	
ICC	$V_{CC} = 5.5 V$	Outputs low			105	mA
		Outputs open			115	

[‡] All typical values are at V_{CC} = 5 V, T_A = 25°C.

[§] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.



SN54ALS29823, SN74ALS29823 9-BIT BUS-INTERFACE FLIP-FLOPS **WITH 3-STATE OUTPUTS**

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switching characteristics (see Figure 1)

	PARAMETER FROM TO TEST CONDITIONS		V _{CC} = MIN T _A = MIN to	to MAX [†] , o MAX [†]	UNIT		
PARAMETER	(INPUT)	(OUTPUT)	TEST CONDITIONS		SN54ALS29823		
				MIN	MAX		
t _{PLH}	CLK	A O	0 50 - 5	2	11.5	ns	
^t PHL	CLK	Any Q	C _L = 50 pF	2	11.5	115	
t _{PLH}	CLK	A O	0 000.5	2	21	ns	
t _{PHL}		Any Q	C _L = 300 pF	2	21	115	
^t PHL	CLR	Any Q	C _L = 50 pF	1	17.5	ns	
^t PZH	ŌĒ	A O	0 50-5	1	17	ns	
tPZL	OE	Any Q	C _L = 50 pF	1	17	115	
^t PZH	ŌĒ	A O	0 200 - 5	1	25	ns	
t _{PZL}	OE	Any Q	C _L = 300 pF	1	29.5	115	
^t PHZ	ŌĒ	4. 0	0 50.5	1	16	no	
tpLZ	OE	Any Q	C _L = 50 pF	1	14	ns	
t _{PHZ}	ŌĒ	Any	C. EnE	1	12	ne	
tpLZ	OE	Any Q	$C_L = 5 pF$	1	11	ns	

T For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V _{CC}		7 V
Input voltage, V _I	5	5.5 V
Voltage applied to a disabled 3-state output	5	5.5 V
Operating free-air temperature range, T _A : SN74ALS29823	0°C to 7	70°C
Storage temperature range	-65°C to 15	50°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			SN74ALS29823		UNIT		
			MIN	NOM	MAX	UNIT	
VCC	Supply voltage		4.75	5	5.25	V	
VIH	High-level input voltage		2			V	
V _{IL}	Low-level input voltage				0.8	V	
IOH	High-level output current				-24	mA	
loL	Low-level output current				48	mA	
	Pulse duration	CLR low	5				
t _W	ruise duration	CLK high or low	5			ns	
		CLR inactive	5				
t _{su}	Setup time before CLK↑	Data	2			ns	
		CLKEN high or low	6				
.	Hold time after CLK↑	CLKEN	0			ns	
th	Hold time after CLK	Data	2			115	
TA	Operating free-air temperature		0	25	70	°C	



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER			SN7	4ALS29	823	UNIT
PARAMETER	TEST CONDITIONS			TYP [†]	MAX	UNIT
VIK	$V_{CC} = 4.75 V,$	I _I = -18 mA			-1.2	V
Vari	Vaa - 4.75.V	$I_{OH} = -15 \text{ mA}$	2.4	3.3		V
VOH	V _{CC} = 4.75 V	$I_{OH} = -24 \text{ mA}$	2	3.1		V
V _{OL}	$V_{CC} = 4.75 V,$	$I_{OL} = 48 \text{ mA}$		0.35	0.5	V
lozh	$V_{CC} = 5.25 V,$	V _O = 2.4 V			20	μΑ
lozL	$V_{CC} = 5.25 V,$	V _O = 0.4 V			-20	μΑ
ΙĮ	$V_{CC} = 5.25 V,$	V _I = 5.5 V			0.1	mA
lін	$V_{CC} = 5.25 V,$	V _I = 2.7 V			20	μΑ
I _{IL}	$V_{CC} = 5.25 V$,	V _I = 0.4 V			-0.2	mA
los [‡]	$V_{CC} = 5.25 V$,	V _O = 0	-75		-250	mA
Icc	$V_{CC} = 5.25 V,$	Outputs open		80	115	mA

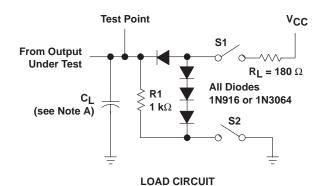
switching characteristics (see Figure 1)

	PARAMETER FROM TO (OUTPUT) TEST CONDITIONS		V _{CC} = MIN T _A = MIN to	to MAX§, o MAX§		
PARAMETER			SN74ALS29823		UNIT	
				MIN	MAX	
t _{PLH}	CLK	A O	0 50-5	2	10	ns
^t PHL	CLK	Any Q	C _L = 50 pF	2	10	115
^t PLH	CLK	A O	0 200 - 5		16	20
t _{PHL}	CLK	Any Q	C _L = 300 pF		16	ns
t _{PHL}	CLR	Any Q	C _L = 50 pF		12	ns
^t PZH	ŌĒ	4. 0	0 50.5		14	no
tpzL	OE	Any Q	C _L = 50 pF		14	ns
^t PZH	ŌĒ	4. 0	0 000 5		20	ns
tpzL	OE	Any Q	C _L = 300 pF		23	115
^t PHZ	ŌĒ	A O	0 50.5		14	no
tpLZ	OE	Any Q	C _L = 50 pF		12	ns
t _{PHZ}	ŌĒ	Any O	C _L = 5 pF		9	ns
^t PLZ	OE	Any Q	OL = 5 PF		9	115

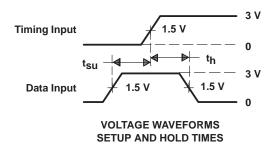
[§] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

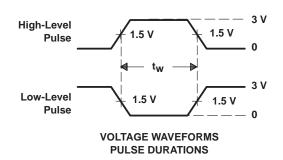
[†] All typical values are at V_{CC} = 5 V, T_A = 25°C. ‡ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

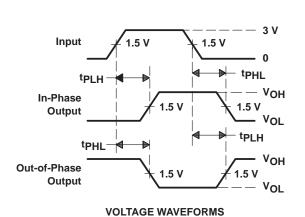
PARAMETER MEASUREMENT INFORMATION

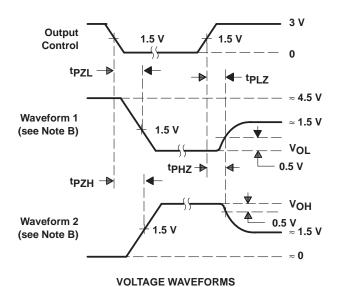


SWITCH POSITION TABLE				
TEST	S 1	S2		
tPLH tPHL tPZH tPZL tPHZ tPHZ	Closed Closed Open Closed Closed Closed	Closed Closed Closed Open Closed Closed		









ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

NOTES: A. C_L includes probe and jig capacitance.

PROPAGATION DELAY TIMES

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f \leq 2.5$ ns, $t_f \leq 2.5$ ns.

Figure 1. Load Circuit and Voltage Waveforms



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